

<b>Notice of References Cited</b>		Application/Control No. 10/528,440	Applicant(s)/Patent Under Reexamination FUJIKAWA ET AL.	
		Examiner Thao P. Le	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,628,871 A	05-1997	Shinagawa, Keisuke	438/514
*	B	US-2003/0194573 A1	10-2003	Itoh et al.	428/461
*	C	US-2003/0190820 A1	10-2003	Hill et al.	438/785
*	D	US-6,700,631 B1	03-2004	Inoue et al.	349/45
*	E	US-6,885,389 B2	04-2005	Inoue et al.	346/45
*	F	US-7,026,650 B2	04-2006	Ryu et al.	257/77
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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